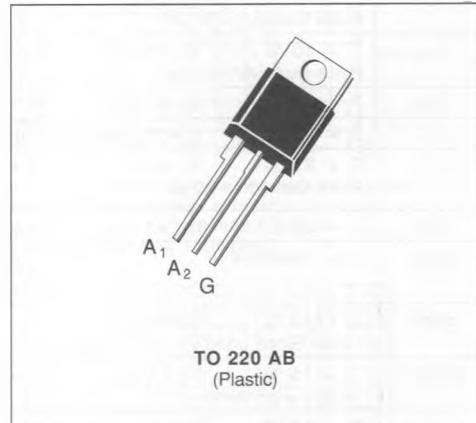


SENSITIVE GATE TRIACS

- GLASS PASSIVATED CHIP
- I_GT SPECIFIED IN FOUR QUADRANTS
- AVAILABLE IN INSULATED VERSION → BTA SERIES (INSULATING VOLTAGE 2500 V_{RMS}) OR IN UNINSULATED VERSION → BTB SERIES
- UL RECOGNIZED FOR BTA SERIES (E81734)



DESCRIPTION

New range suited for applications such as phase control and static switching.

ABSOLUTE RATINGS (limiting values)

Symbol	Parameter	Value		Unit
I _{T(RMS)}	RMS on-state Current (360° conduction angle)	T _C = 75 °C	8	A
I _{TSM}	Non Repetitive Surge Peak on-state Current (T _j initial = 25 °C - Half sine wave)	t = 8.3 ms	84	A
		t = 10 ms	80	
I ² t	I ² t Value for Fusing	t = 10 ms	32	A ² s
di/dt	Critical Rate of Rise of on-state Current (1)	Repetitive F = 50 Hz	10	A/μs
		Non Repetitive	50	
T _{sig} T _i	Storage and Operating Junction Temperature Range		-40 to 150 -40 to 110	°C °C

Symbol	Parameter	BTA/BTB 08-					Unit
		200S	400S	600S	700S	800S	
V _{DRM}	Repetitive Peak off-state Voltage (2)	200	400	600	700	800	V

(1) I_G = 100 mA di/dt = 1 A/μs

(2) T_j = 110 °C.

THERMAL RESISTANCES

Symbol	Parameter	Value		Unit
R _{th (j-a)}	Junction to Ambient	60		°C/W
R _{th (j-c) DC}	Junction to Case for DC	5.1		°C/W
R _{th (j-c) AC}	Junction to Case for 360 ° Conduction Angle (F = 50 Hz)	3.8		°C/W

GATE CHARACTERISTICS (maximum values)

$P_{GM} = 40 \text{ W}$ ($t_p = 10 \mu\text{s}$) $I_{GM} = 4 \text{ A}$ ($t_p = 10 \mu\text{s}$)
 $P_G(\text{AV}) = 1 \text{ W}$ $V_{GM} = 16 \text{ V}$ ($t_p = 10 \mu\text{s}$)

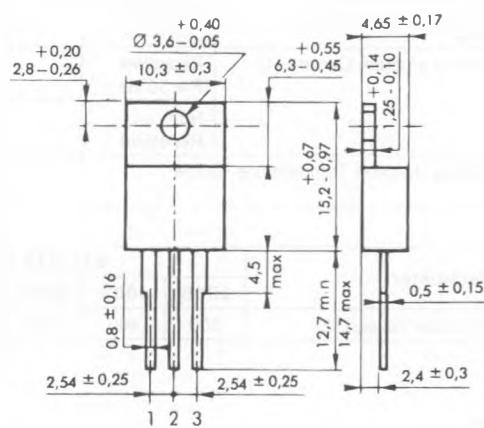
ELECTRICAL CHARACTERISTICS

Symbol	Test Conditions			Quadrants	Min.	Typ.	Max.	Unit
I_{GT}	$T_j = 25^\circ\text{C}$	$V_D = 12 \text{ V}$	$R_L = 33 \Omega$	I-II-III-IV			10	mA
	Pulse Duration > 20 μs							
V_{GT}	$T_j = 25^\circ\text{C}$	$V_D = 12 \text{ V}$	$R_L = 33 \Omega$	I-II-III-IV			1.5	V
	Pulse Duration > 20 μs							
V_{GD}	$T_j = 110^\circ\text{C}$	$V_D = V_{DRM}$	$R_L = 3.3 \text{ k}\Omega$	I-II-III-IV	0.2			V
I_H^*	$T_j = 25^\circ\text{C}$	$I_T = 100 \text{ mA}$	Gate Open				25	mA
I_L	$T_j = 25^\circ\text{C}$	$V_D = 12 \text{ V}$	$I_G = 20 \text{ mA}$	I-III-IV		25		mA
				II		50		
V_{TM}^*	$T_j = 25^\circ\text{C}$	$I_{TM} = 11 \text{ A}$	$t_p = 10 \text{ ms}$				1.75	V
I_{DRM}^*	V_{DRM} Specified		$T_j = 25^\circ\text{C}$				0.01	mA
			$T_j = 110^\circ\text{C}$				0.5	
dv/dt^*	$T_j = 110^\circ\text{C}$	Gate Open Linear Slope up to $V_D = 67\% V_{DRM}$			10			V/ μs
$(dv/dt)_c^*$	$T_C = 75^\circ\text{C}$	$V_D = V_{DRM}$	$I_T = 11 \text{ A}$			5		V/ μs
t_{gt}	$T_j = 25^\circ\text{C}$	$V_D = V_{DRM}$	$I_T = 11 \text{ A}$	I-II-III-IV		2		μs
	$I_G = 40 \text{ mA}$	$dv/dt = 0.45 \text{ A}/\mu\text{s}$						

* For either polarity of electrode A_2 voltage with reference to electrode A_1 .

PACKAGE MECHANICAL DATA

TO 220 AB Plastic



Triac : 1 2 3 = $A_1 A_2 G$

Cooling method : by conduction (method C)

Marking : type number

Weight : 2 g

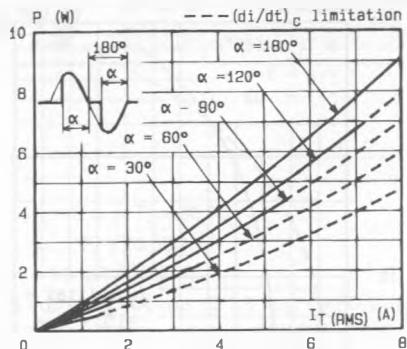


Fig.1 - Maximum mean power dissipation versus RMS on-state current ($F = 60$ Hz).

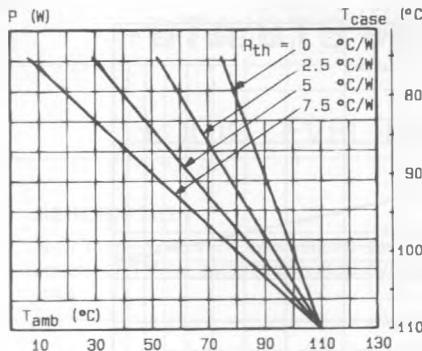


Fig.2 - Correlation between maximum mean power dissipation and maximum allowable temperatures (T_{amb} and T_{case}) for different thermal resistances heatsink + contact.

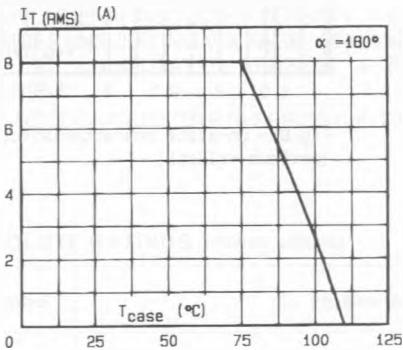


Fig.3 - RMS on-state current versus case temperature.

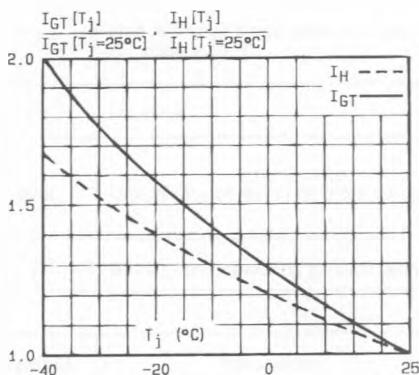


Fig.5 - Relative variation of gate trigger current and holding current versus junction temperature.

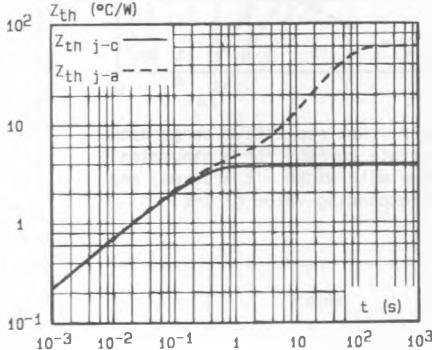


Fig.4 - Thermal transient impedance junction to case and junction to ambient versus pulse duration.

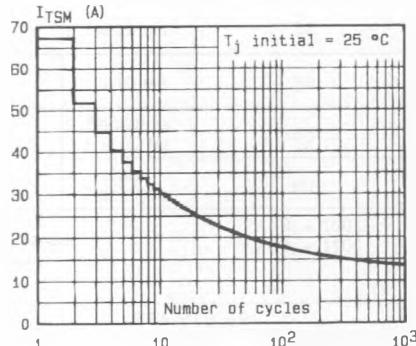


Fig.6 - Non repetitive surge peak on-state current versus number of cycles.

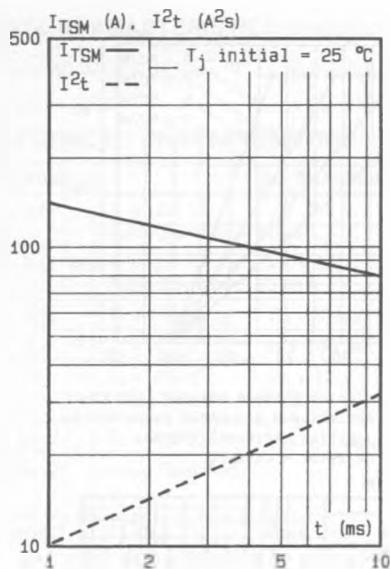


Fig.7 - Non repetitive surge peak on-state current for a sinusoidal pulse with width : $t \leq 10$ ms, and corresponding value of I^2t .

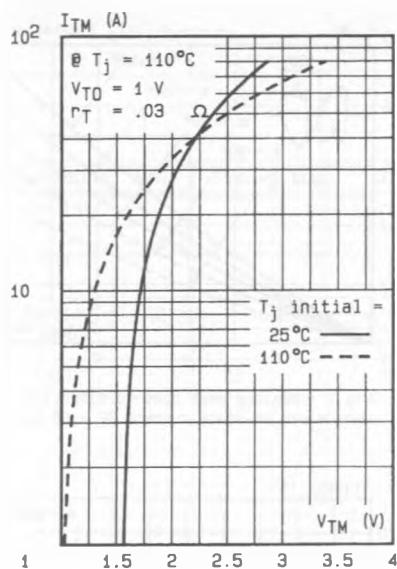


Fig.8 - On-state characteristics (maximum values).